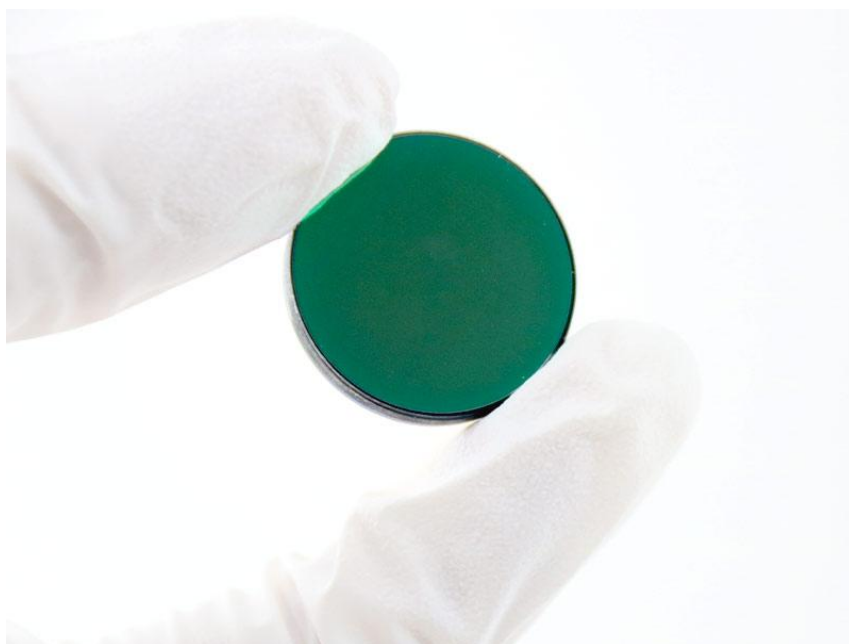


1535nm 带通滤光片



描述

高透过率，减少光学系统的信号损失，提升光学系统的性能，适用于激光系统、光谱分析、光通信和其他高端光学应用。

产品特点

特定波长选择性、高透过率、耐用材料

产品型号

BP-1535-080 nm

应用领域

荧光显微镜

光谱学

研究与测试

核心参数

中心波长	基材	厚度	中心波长偏差	半宽高带宽偏差	透射率
1535nm	N-bk7	1mm	±6nm	±6nm	>75%

详细参数

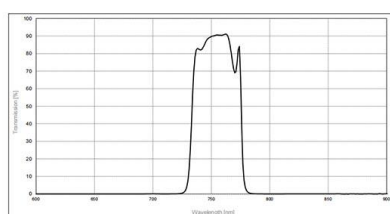
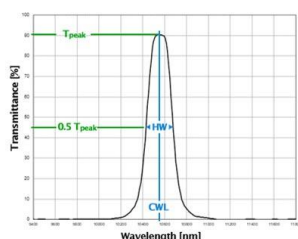
型号	基材	厚度 (mm)	中心波 长偏差 (± nm)	半宽 高带 宽偏 差(± nm)	透射率 (> %)	Block high
BP-0456-042 nm	Cemented	5	5	5	50	1200
BP-0750-040 nm	Colour glass	1.8	7	7	70	1200
BP-1112-060 nm	Glass	1.1	10	5	50	3000
BP-1535-080 nm	N-bk7	1	6	6	75	2500
BP-1695-095 nm	Cemented	1	20	20	70	3500
BP-2010-113 nm	Cemented	0.8	15	15	60	3500
BP-3330-145 nm	Sapphire	0.5	30	20	70	30000
BP-5220-300 nm	Sapphire	1	50	35	50	30000
BP-10600-848 nm	Germanium	1	100	100	80	18500

BP-15118-1260	Germanium	1	310	150	60	20000
nm						

型号：BP-CWL-HW，单位为纳米（HW 50 % Tpeak）

每种类型的滤光片均提供室温和法线入射角下的光谱曲线。其余波长滤光片也可提供，如有需求请下载文档查看。

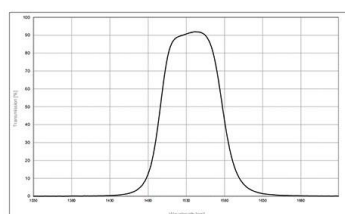
特性曲线



Date: 2024-01-17
Operator: SP
Article:
Art no: 713M
BP-0750-040 nm Ø25.4x1.8 mm
Specifications:
CWL: 750.17 nm
HW: 40.17 nm
Blocking: 190 – 1200 nm (0.1 %)
T high min 70 %

Measured values:
CWL = 754.52 nm...OK
HW = 42.89 nm...OK
Cutoff 5 % = 729.26 nm
Cutoff 5 % = 778.21 nm
HP1 = 733.32 nm
HP2 = 775.71 nm
Tpeak = 91.1 %
Tavg = 85.91 %
Slope 1 = 0.83 %
Slope 2 = 0.53 %

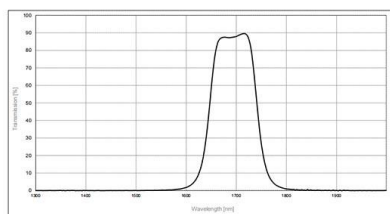
Measurement conditions:
Temperature: 296 K AOI: 0 °



Date: 2022-02-09
Operator: DJJ
Article:
Art no: 713M
BP-1515-040 nm Ø25.4x1.8 mm
Specifications:
CWL: 1515.86 nm
HW: 80.0 nm
Tmin: 75 %
Blocking: 200 - 2500 nm (20 %)

Measured values:
CWL = 1516.77 nm...OK
HW = 83.82 nm...OK
Cutoff 5 % = 1465.63 nm
Cutoff 5 % = 1565.26 nm
HP1 = 1504.86 nm
HP2 = 1576.68 nm
Tpeak = 85.16 %...OK
Tavg = 85.86 %
Slope 1 = 2.35 %
Slope 2 = 2.6 %

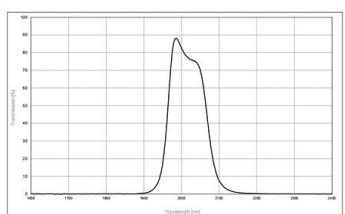
Measurement conditions:
Temperature: 23 °C
AOI: 0 deg



Date: 2023-10-23
Operator: DG
Article:
Art no: 713M
BP-1695-095 nm Ø25.4x1.8 mm
Specifications:
CWL: 1695.120 nm
HW: 95.20 nm
Blocking: 200 – 3500 nm (0.1 %)
T high min 70 %

Measured values:
CWL = 1696.1 nm...OK
HW = 97.26 nm...OK
Cutoff 5 % = 1616.17 nm
Cutoff 5 % = 1772.23 nm
HP1 = 1645.47 nm
HP2 = 1762.72 nm
Tpeak = 89.6 %
Tavg = 87.26 %
Slope 1 = 2.34 %
Slope 2 = 2.23 %

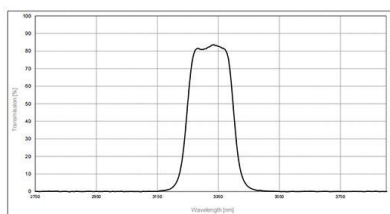
Measurement conditions:
Temperature: 296 K AOI: 0 °



Date: 2019-05-01
Operator: EBD
Article:
Art no: 713M
BP-2010-113 nm Ø25.4x1.8 mm
Specifications:
CWL: 2010.113 nm
HW: 113.113 nm
Tmin: 75 %
Blocking: 190 - 3500 nm (20 %)

Measured values:
CWL = 2010.07 nm...OK
HW = 105.67 nm...OK
Cutoff 5 % = 1953.59 nm
Cutoff 5 % = 2066.24 nm
HP1 = 1962.26 nm
HP2 = 2049.89 nm
Tpeak = 88.38 %...OK
Tavg = 86.5 %
Slope 1 = 1.9 %
Slope 2 = 2.87 %

Measurement conditions:
Temperature: 23 °C
AOI: 0 deg



Date: 2024-08-01
Operator: NLY
Article:
Art no: 713M
BP-3330-165 nm Ø25.4x1.8 mm
Specifications:
CWL: 3330.130 nm
HW: 145.120 nm
B: 100–3000 nm avg 0.1%
T high min 70 %

Measured values:
CWL = 3332.85 nm...OK
HW = 156.51 nm...OK
Cutoff 5 % = 3211.76 nm
Cutoff 5 % = 3437.49 nm
HP1 = 3245.6 nm
HP2 = 3402.11 nm
Tpeak = 83.53 %
Tavg = 81.81 %
Slope 1 = 1.41 %
Slope 2 = 1.41 %

Measurement conditions:
Temperature: 296 K AOI: 0 °